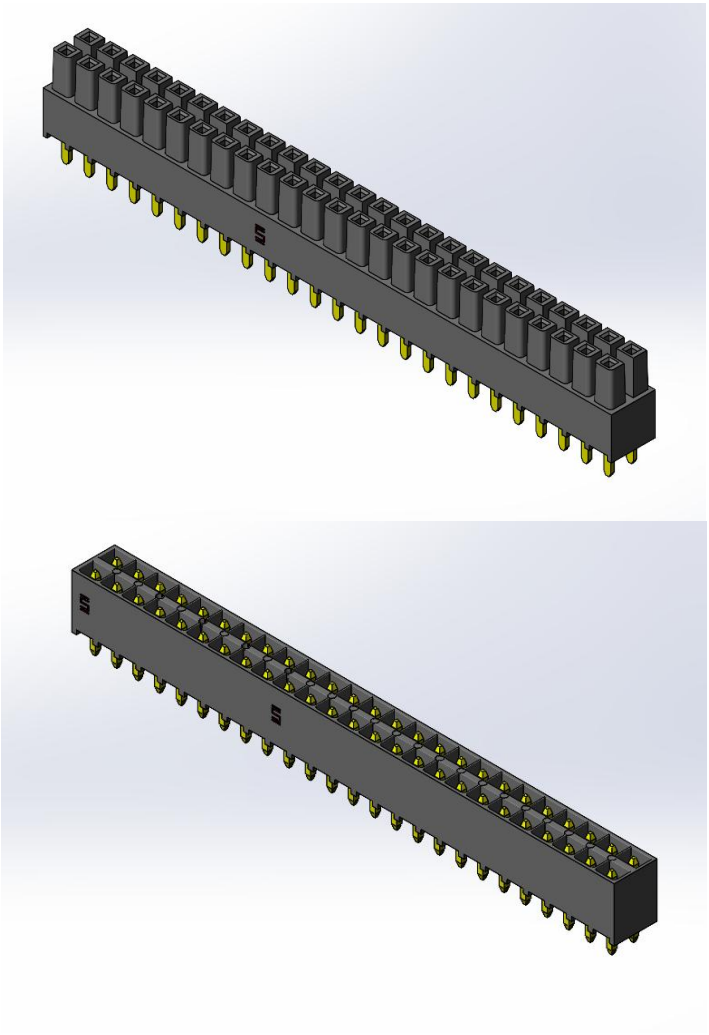
Project Number: Design Qualification Test Report	Tracking Code: CR-1325206_Report_Rev_1
Requested by: Mark Shireman	Date: 8/10/2026
Part #: IPS1-125-01-S-D/ IPT1-125-01-S-D	
Part description: IPS1/IPT1	Tech: Danton Gan
Test Start: 11/17/2025	Test Completed: 5/22/2026



DESIGN QUALIFICATION TEST REPORT

IPS1/IPT1
IPS1-125-01-S-D/ IPT1-125-01-S-D

REVISION HISTORY

DATE	REV.NUM.	DESCRIPTION	ENG
3/24/2026	**1**	**Initial Issue**	**DG**

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to IS0 10012-l and ANSI/NCSL 2540-1, as applicable.

SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364.

TEST SAMPLES AND PREPARATION

1) All materials were manufactured in accordance with the applicable product specification.
2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
5) The automated procedure is used with aqueous compatible soldering materials.
6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
7) Any additional preparation will be noted in the individual test sequences.
8) Solder Information: Lead Free
9) Samtec Test PCBs used: PCB-114477-TST

FLOWCHARTS

IR/DWV

Pin-to-Pin

Group 1 IPS1-125-01-S-D IPT1-125-01-S-D 2 Assemblies		Group 2 IPS1-125-01-S-D 2 Assemblies		Group 3 IPT1-125-01-S-D 2 Assemblies		Group 4 IPS1-125-01-S-D IPT1-125-01-S-D 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)
						2.	DWV at Test Voltage (1)
						3.	Thermal Shock (5)
						4.	IR (4)
						5.	DWV at Test Voltage (1)
						6.	Humidity (3)
						7.	IR (4)
						8.	DWV at Test Voltage (1)

Row-to-Row

Group 5 IPS1-125-01-S-D IPT1-125-01-S-D 2 Assemblies		Group 6 IPS1-125-01-S-D 2 Assemblies		Group 7 IPT1-125-01-S-D 2 Assemblies		Group 8 IPS1-125-01-S-D IPT1-125-01-S-D 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)
						2.	DWV at Test Voltage (1)
						3.	Thermal Shock (5)
						4.	IR (4)
						5.	DWV at Test Voltage (1)
						6.	Humidity (3)
						7.	IR (4)
						8.	DWV at Test Voltage (1)

(1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(2) DWV Breakdown = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(3) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(4) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max

(5) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS

Mechanical Shock/Random Vibration/LLCR

Group 1
IPS1-125-01-S-D
IPT1-125-01-S-D
8 Assemblies

Step	Description
1.	LLCR (1)
2.	Mechanical Shock (2)
3.	Random Vibration (3)
4.	LLCR (1) Max Delta = 15 mOhm

(1) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27
Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

Mechanical Shock/Random Vibration/Event Detection

Group 1
IPS1-125-01-S-D
IPT1-125-01-S-D
60 Points

Step	Description
1.	Nanosecond Event Detection (Mechanical Shock) (1)
2.	Nanosecond Event Detection (Random Vibration) (2)

(1) Nanosecond Event Detection (Mechanical Shock)
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-27 for Mechanical Shock:
Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-28 for Random Vibration:
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

FLOWCHARTS

Current Carrying Capacity

Group 1
IPS1-125-01-S-D
IPT1-125-01-S-D
2 Pins Powered
Signal

Step	Description
1.	CCC (1) Number of Positions = 1 Rows = 2

Group 2
IPS1-125-01-S-D
IPT1-125-01-S-D
4 Pins Powered
Signal

Step	Description
1.	CCC (1) Number of Positions = 2 Rows = 2

Group 3
IPS1-125-01-S-D
IPT1-125-01-S-D
6 Pins Powered
Signal

Step	Description
1.	CCC (1) Number of Positions = 3 Rows = 2

Group 4
IPS1-125-01-S-D
IPT1-125-01-S-D
8 Pins Powered
Signal

Step	Description
1.	CCC (1) Number of Positions = 4 Rows = 2

Group 5
IPS1-125-01-S-D
IPT1-125-01-S-D
50 Pins Powered
Signal

Step	Description
1.	CCC (1) Rows = 2 Number of Positions = 25

(1) CCC = EIA-364-70
Method 2, Temperature Rise Versus Current Curve
(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C
(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

Current Cycling

Group 1
IPS1-125-01-S-D
IPT1-125-01-S-D
8 Assemblies
Signal

Step	Description
1.	Current Cycle (1)

(1) Current Cycle = EIA 364-55
Test Condition = B (125% Rated Current)
Method = 4 (On: 45 Minutes, Off: 15 Minutes)
Number of Cycles = 500

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.*
2) Test Condition 1: -55°C to +85°C
3) Test Time: ½ hour dwell at each temperature extreme
4) Number of Cycles: 100
5) All test samples are pre-conditioned at ambient.
6) All test samples are exposed to environmental stress in mated conditions.

HUMIDITY:

1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors.*
2) Test Condition B, 240 Hours.
3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
4) All samples are pre-conditioned at ambient.
5) All test samples are exposed to environmental stress in mated conditions.

LLCR:

1) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
2) A computer program, LLCR 221.exe, ensures repeatability for data acquisition.
3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
    a. <= +5.0 mOhms:----------Stable
    b. +5.1 to +10.0 mOhms:----------Minor
    c. +10.1 to +15.0 mOhms: ----------Acceptable
    d. +15.1 to +50.0 mOhms: ----------Marginal
    e. +50.1 to +1000 mOhms:----------Unstable
    f. >+1000 mOhms:----------Open Failure

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:
    a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Electrification Time 2.0 minutes
        iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
2) MEASUREMENTS:
3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at their rated voltage and withstand momentary over potentials due to switching, surges, and another similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

1) PROCEDURE:
    a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Barometric Test Condition 1
        iii. Rate of Application 500 V/Sec
        iv. Test Voltage (VAC) until breakdown occurs
2) MEASUREMENTS/CALCULATIONS
    a. The breakdown voltage shall be measured and recorded.
    b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
    c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

MECHANICAL SHOCK (Specified Pulse):

1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
2) Test Condition C
3) Peak Value: 100 G
4) Duration: 6 Milliseconds
5) Wave Form: Half Sine
6) Velocity: 12.3 ft/s
7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
2) Test Condition V, Letter B
3) Power Spectral Density: 0.04 G^2 / Hz
4) G 'RMS': 7.56
5) Frequency: 50 to 2000 Hz
6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
2) Prior to testing, the samples were characterized to ensure the low nanosecond event being monitored will trigger the detector.
3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

TEMPERATURE RISE (Current Carrying Capacity, CCC):

1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
4) The size of the temperature probe can affect the measured temperature.
5) Copper traces on PC boards will contribute to temperature rise:
    a. Self-heating (resistive)
    b. Reduction in heat sink capacity affecting the heated contacts
6) A de-rating curve, usually 20%, is calculated.
7) Calculated de-rated currents at three temperature points are reported:
    a. Ambient
    b. 85^{o} C
    c. 95^{o} C
    d. 115^{o} C
8) Typically, neighboring contacts (in close proximity to maximize heat buildup) are energized.
9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
11) Hook-up wire cross section is larger than the cross section of any connector that leads/PC board traces, jumpers, etc.
12) Hook-up wire length is longer than the minimum specified in the referencing standard.

CURRENT CYCLING

1. Reference document: EIA-364-55, *Current Cycling Test Procedure for Electrical Connectors*.
2. Current Cycling shall be performed in accordance with EIA-364-55, Test Condition
3. Testing shall be as follows:
    - 3.1. Test Current: 2.8 Amps (125% of 30°C Rating)
    - 3.2. "ON" Time: 45 Minutes
    - 3.3. "OFF" Time: 15 Minutes
    - 3.4. Number of Cycles: 500
    - 3.5. Measurements: 40 minutes into ON cycle
        - 3.5.1. Temperature
        - 3.5.2. Voltage Drop/Contact Resistance
4. Temperature vs. Number of Cycles and Voltage Drop vs. Number of Cycles shall be measured and recorded.

RESULTS

Insulation Resistance minimums, IR

Pin to Pin

- **Initial**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated ---------- 6100 Meg Ω ---------- Passed**
  - **Unmated ---------- 13400 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**

Row to Row

- **Initial**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated ---------- 45000 Meg Ω ---------- Passed**
  - **Unmated ---------- 45000 Meg Ω ---------- Passed**

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
  - **Breakdown Voltage ---------- 2257 VAC**
  - **Test Voltage ---------- 1693 VAC**
  - **Working Voltage ---------- 564 VAC**

Pin to Pin

- **Initial DWV ---------- Passed**
- **Thermal DWV ---------- Passed**
- **Humidity DWV ---------- Passed**

Row to Row

- **Initial DWV ---------- Passed**
- **Thermal DWV ---------- Passed**
- **Humidity DWV ---------- Passed**

RESULTS Continued

LLCR Shock & Vibration: (192 Signal LLCR test points)

- **Initial ----------4.25 mOhms Max**
- **Shock &Vibration**
  - **<= +5.0 mOhms----------192 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ----------0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ----------0Points---------- Acceptable**
  - **+15.1 to +50.0 mOhms ----------0 Points ---------- Marginal**
  - **+50.1 to +1000 mOhms----------0 Points ---------- Unstable**
  - **>+1000 mOhms----------0 Points ---------- Open Failure**

Mechanical Shock & Random Vibration:

- **Shock**
  - **No Damage---------- ---------- Pass**
  - **50 Nanoseconds ---------- ---------- Pass**
- **Vibration**
  - **No Damage---------- ---------- Pass**
  - **50 Nanoseconds ---------- ---------- Pass**

Temperature Rise, CCC at a 20% de-rating

- **CCC for a 30°C Temperature Rise----------6.2 A per contact with 1 contact (2 x 1) powered**
- **CCC for a 30°C Temperature Rise----------4.9 A per contact with 2 contacts (2 x 2) powered**
- **CCC for a 30°C Temperature Rise----------4.0 A per contact with 3 contacts (2 x 3) powered**
- **CCC for a 30°C Temperature Rise----------3.6 A per contact with 4 contacts (2 x 4) powered**
- **CCC for a 30°C Temperature Rise----------2.2 A per contact with 5 contacts (2 x 25) powered**

Current Cycling

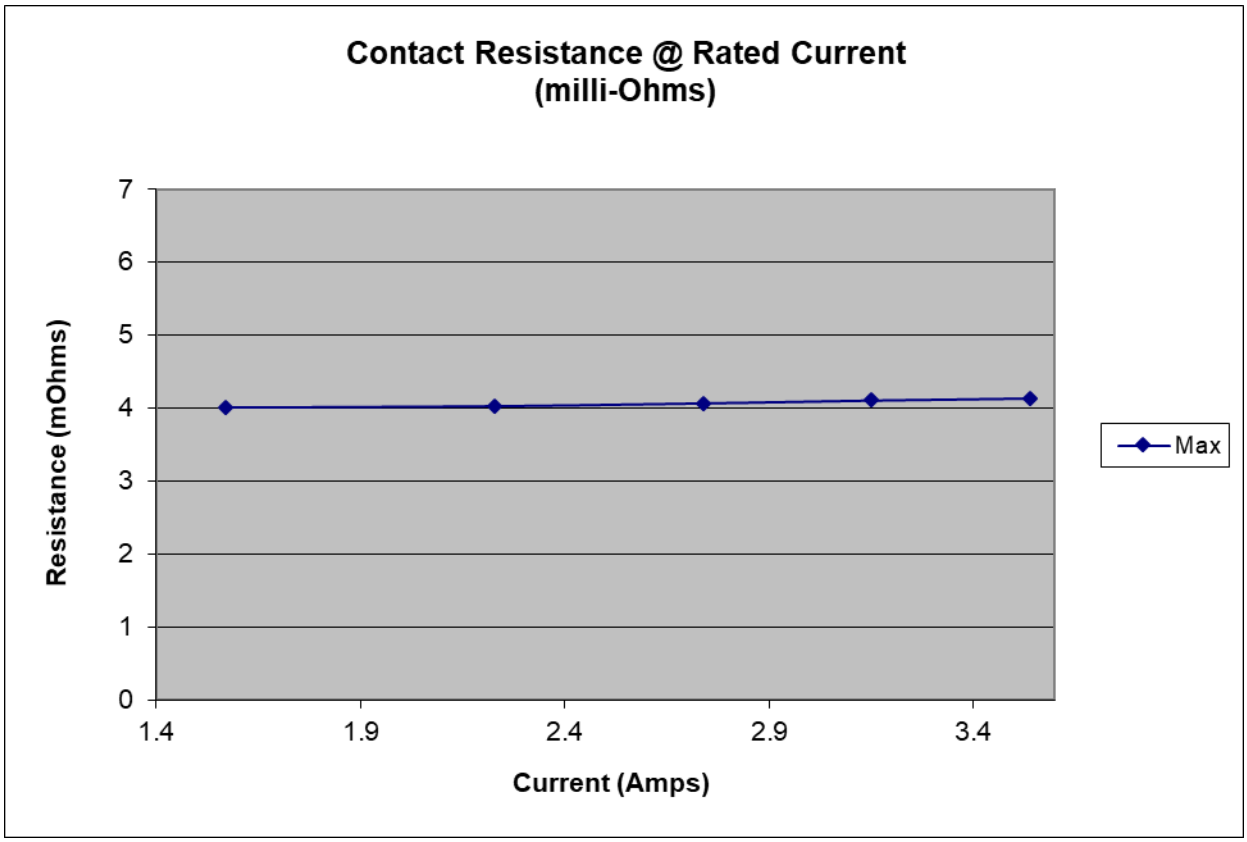
Test Condition: 500 Cycles, 45 minutes ON and 15 minutes OFF

- **Test Current ---------- 2.8 Amps**
- **Contact Resistances, Measured 40 minutes into the FIRST and LAST ON cycle**
  - **Initial**
    - **Min ---------- 4.45 mOhms**
    - **Max---------- 5.14 mOhms**
  - **Final**
    - **Min ---------- 4.45 mOhms**
    - **Max---------- 5.14 mOhms**
- **Temperature Change, Measured 40 minutes into the FIRST and LAST ON cycle**
  - **Initial Temperature Change ----------30.4°C**
  - **Final Temperature Change ----------30.4°C**

RESULTS Continued

CONTACT RESISTANCE @ RATED CURRENT - DC Resistance (DCR)

The following data represents the Voltage drop and Contact Resistance at Rated Current for the 100% energized samples:



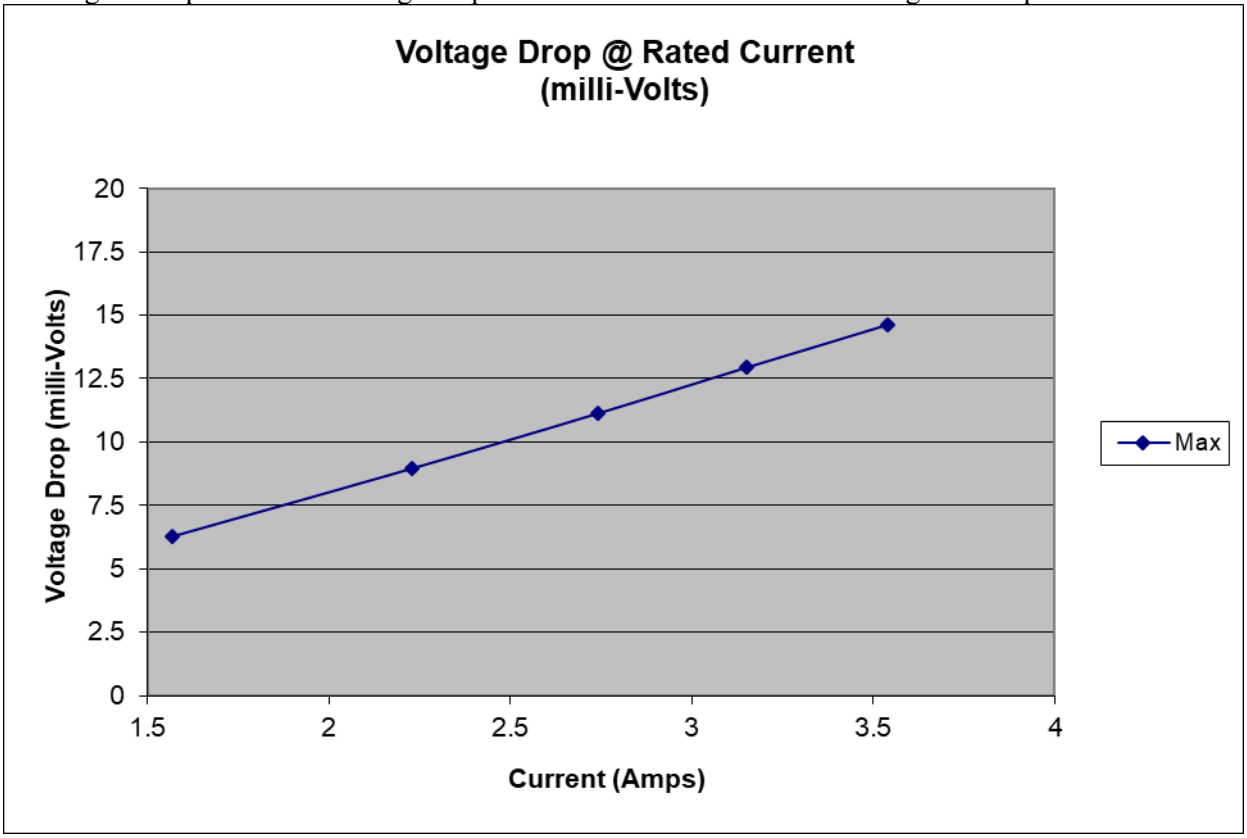
CONTACT RESISTANCE DATA
ALL CONTACTS ENERGIZED
(mΩ)

TEST CURRENT AMPS	1.57	2.23	2.74	3.15	3.54
Min	3.45	3.45	3.47	3.51	3.54
Max	4.01	4.03	4.07	4.11	4.14
Avg	3.65	3.66	3.69	3.73	3.76

RESULTS Continued

VOLTAGE DROP @ RATED CURRENT

The following data represents the Voltage drop at Rated Current for the 100% energized samples:



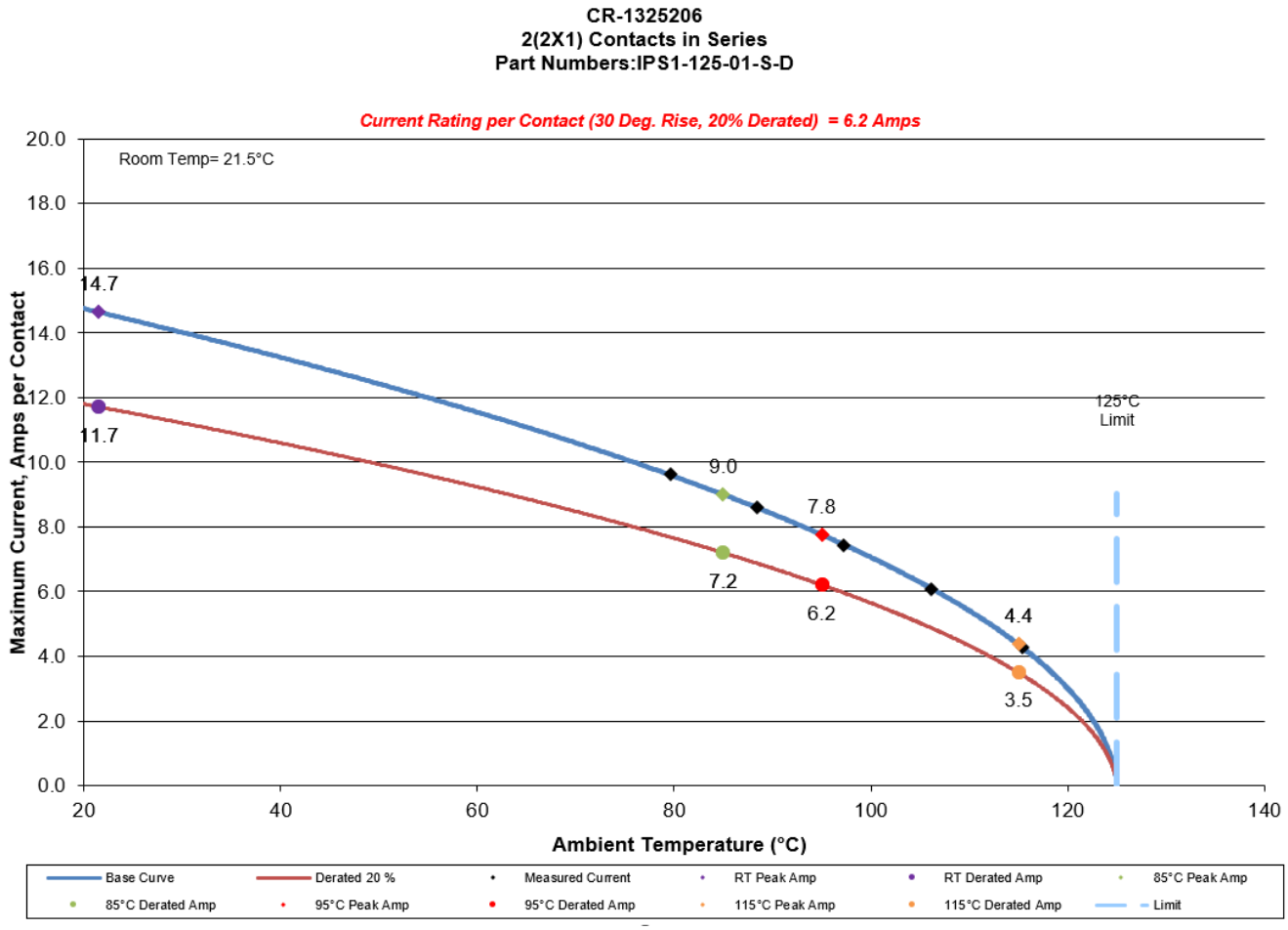
VOLTAGE DROP DATA ALL CONTACTS ENERGIZED (mV)					
TEST CURRENT AMPS	1.57	2.23	2.74	3.15	3.54
Min	5.41	7.69	9.52	11.07	12.53
Max	6.3	8.98	11.14	12.95	14.64
Avg	5.77	8.21	10.18	11.84	13.38

DATA SUMMARIES

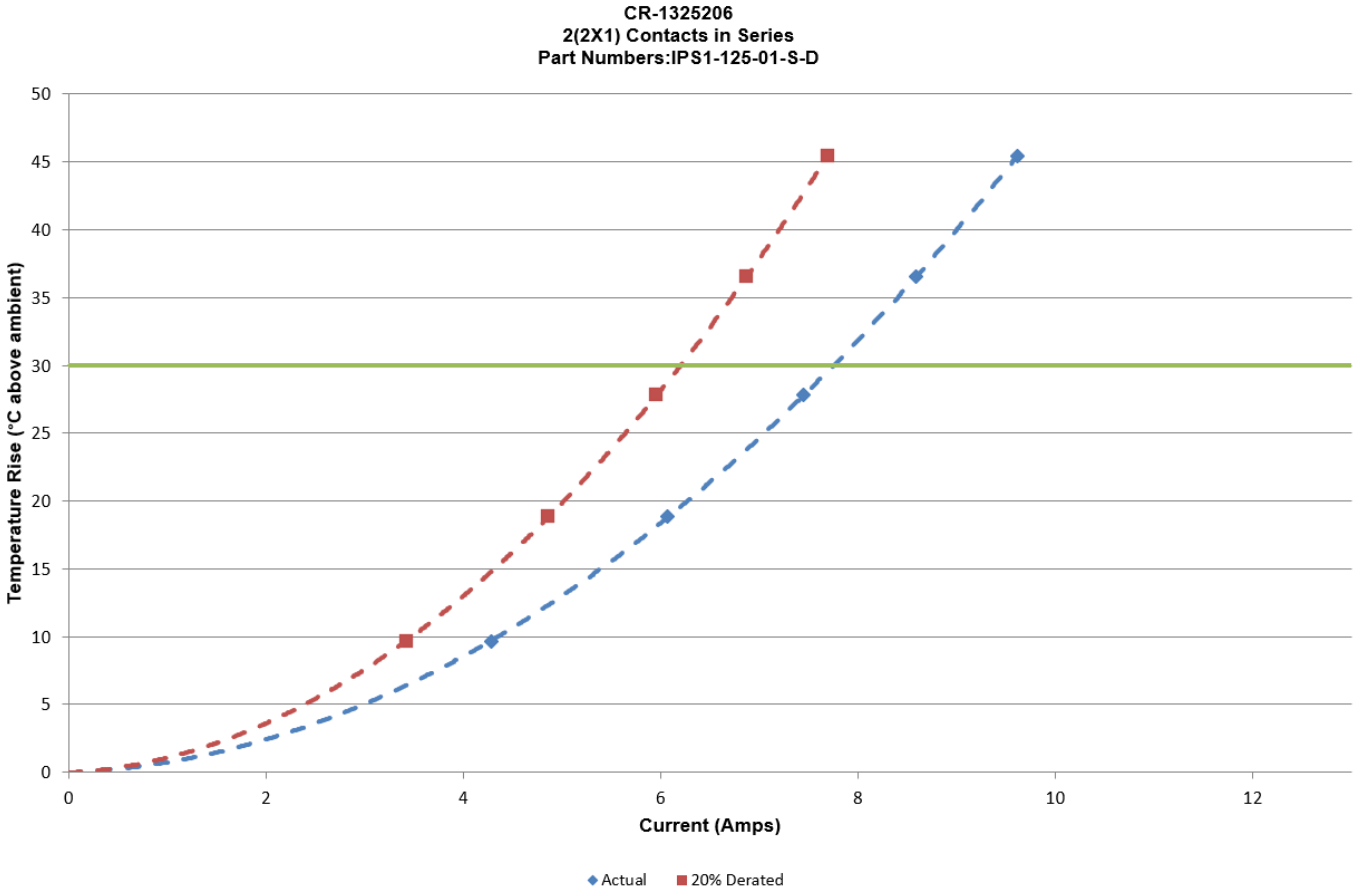
TEMPERATURE RISE (Current Carrying Capacity, CCC):

1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
3) Temperature readings are recorded for which three successive readings, 15 minutes apart, differ less than 1° C (computer-controlled data acquisition).
4) Adjacent contacts were powered:

    a. Linear configuration with 2 adjacent contacts powered

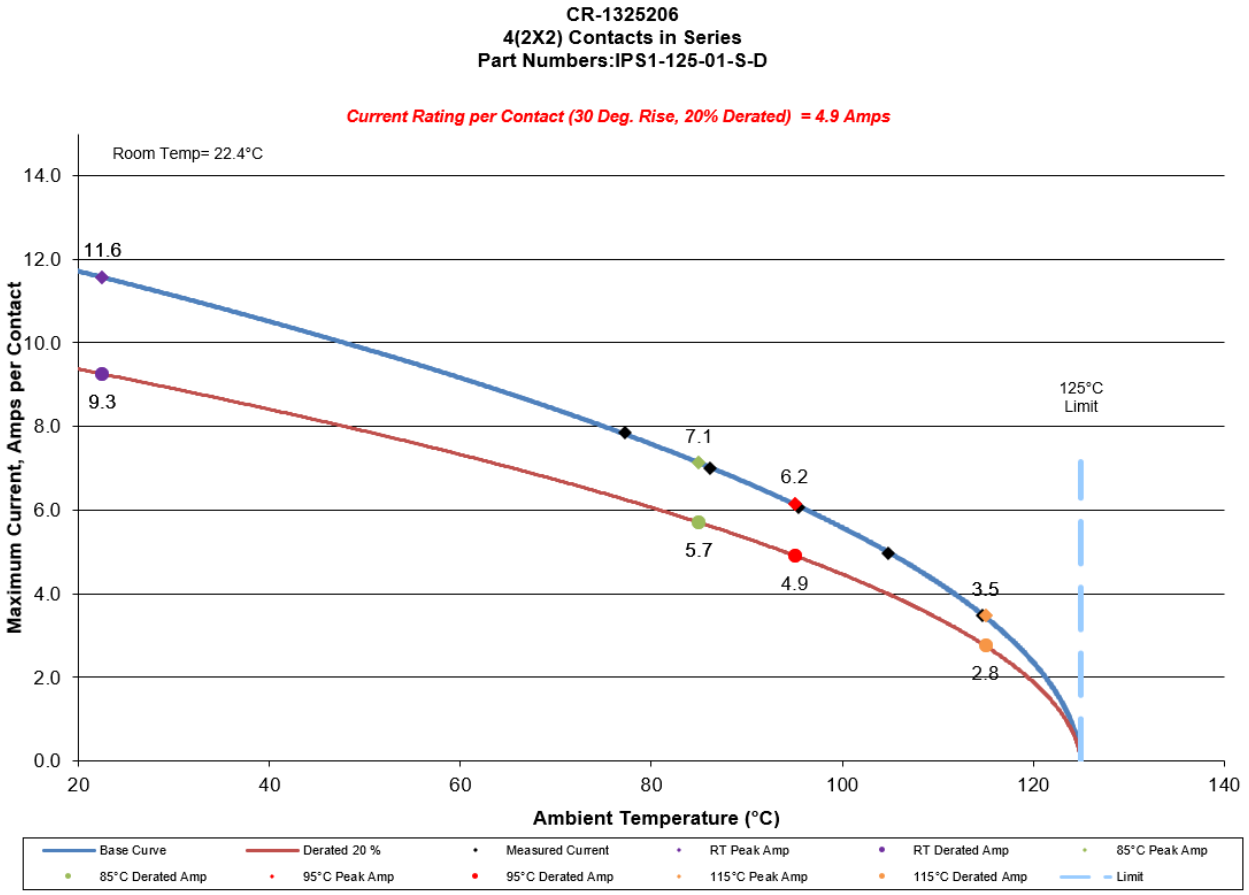


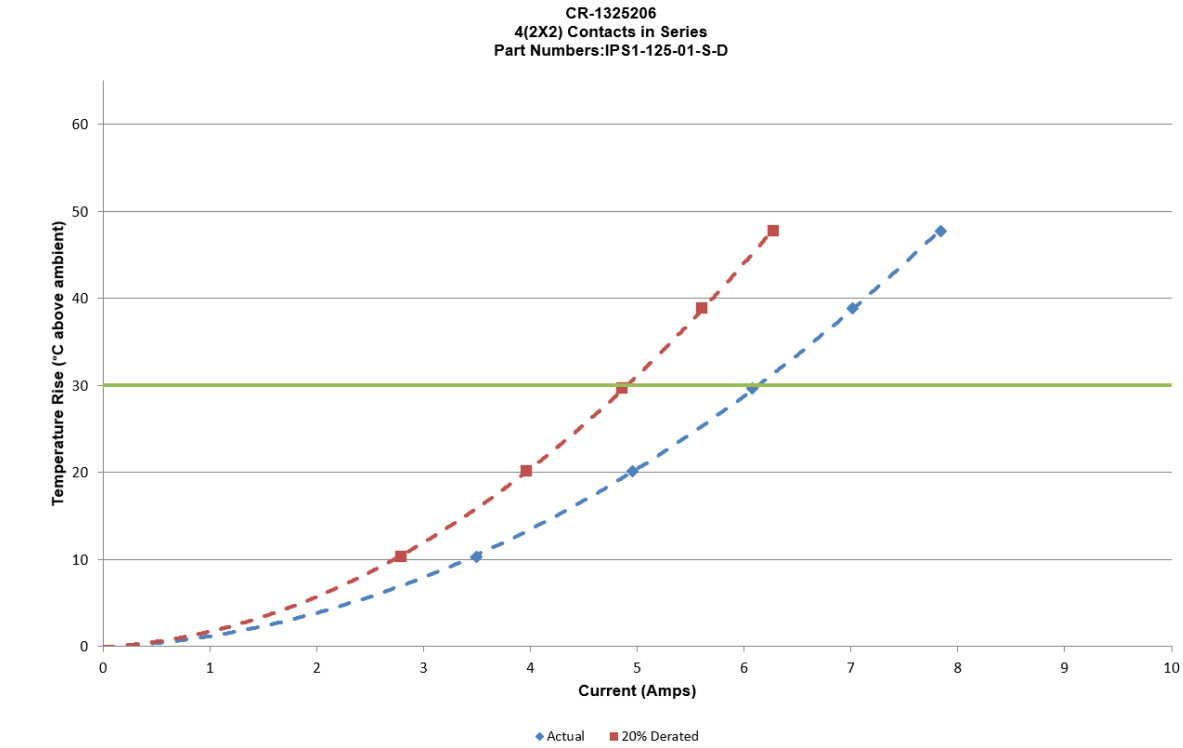
DATA SUMMARIES CONTINUED



DATA SUMMARIES CONTINUED

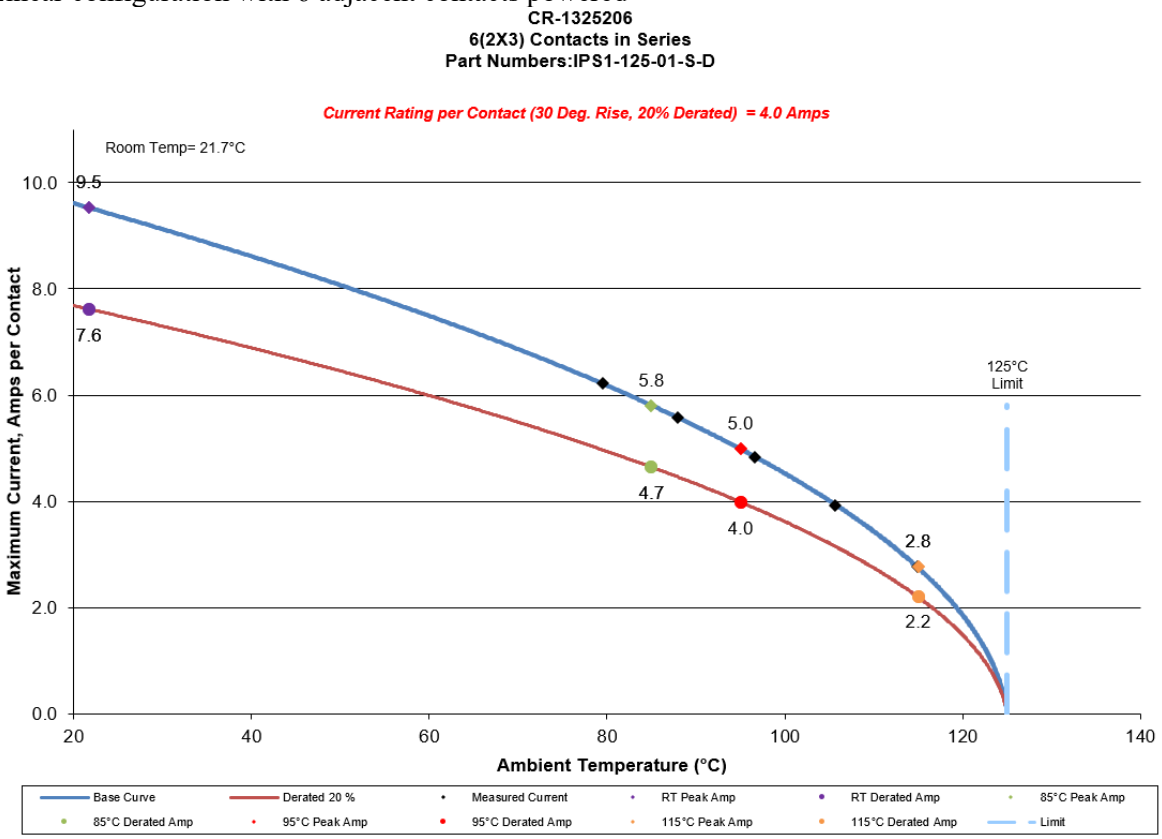
b. Linear configuration with 4 adjacent contacts powered

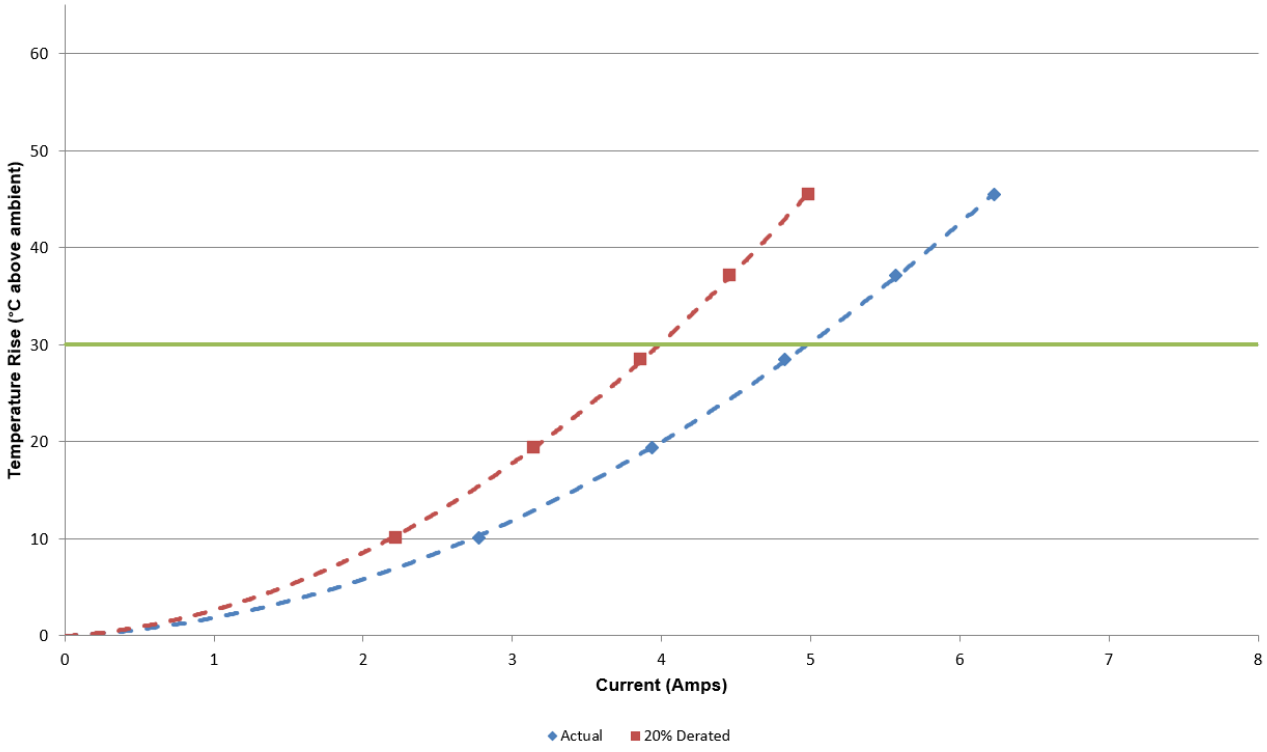




DATA SUMMARIES CONTINUED

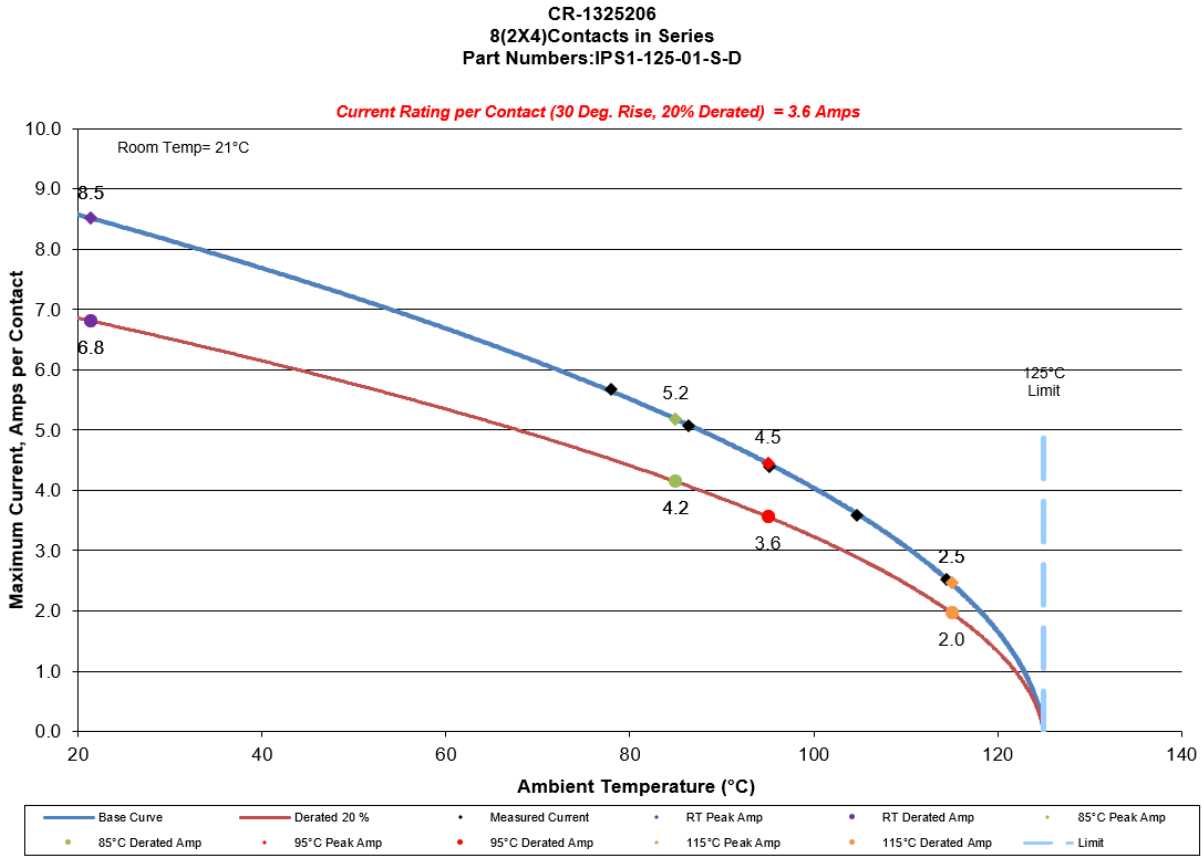
c. Linear configuration with 6 adjacent contacts powered

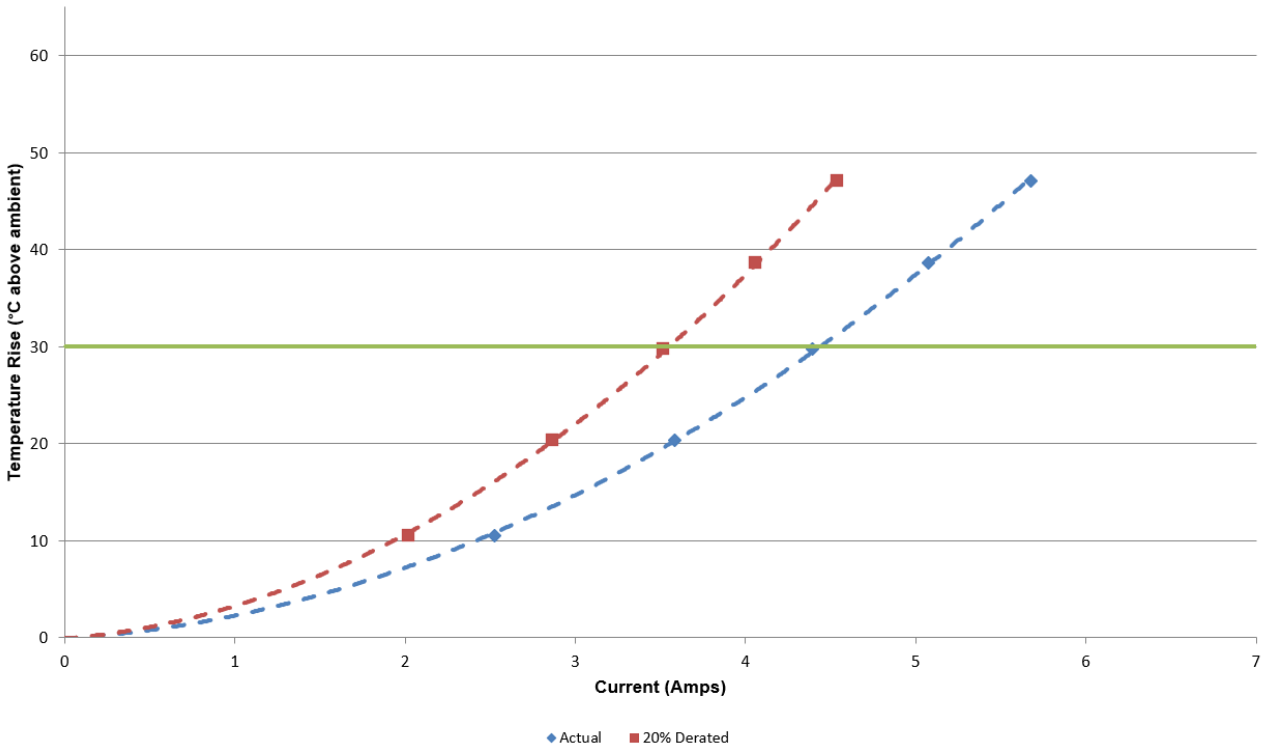




DATA SUMMARIES CONTINUED

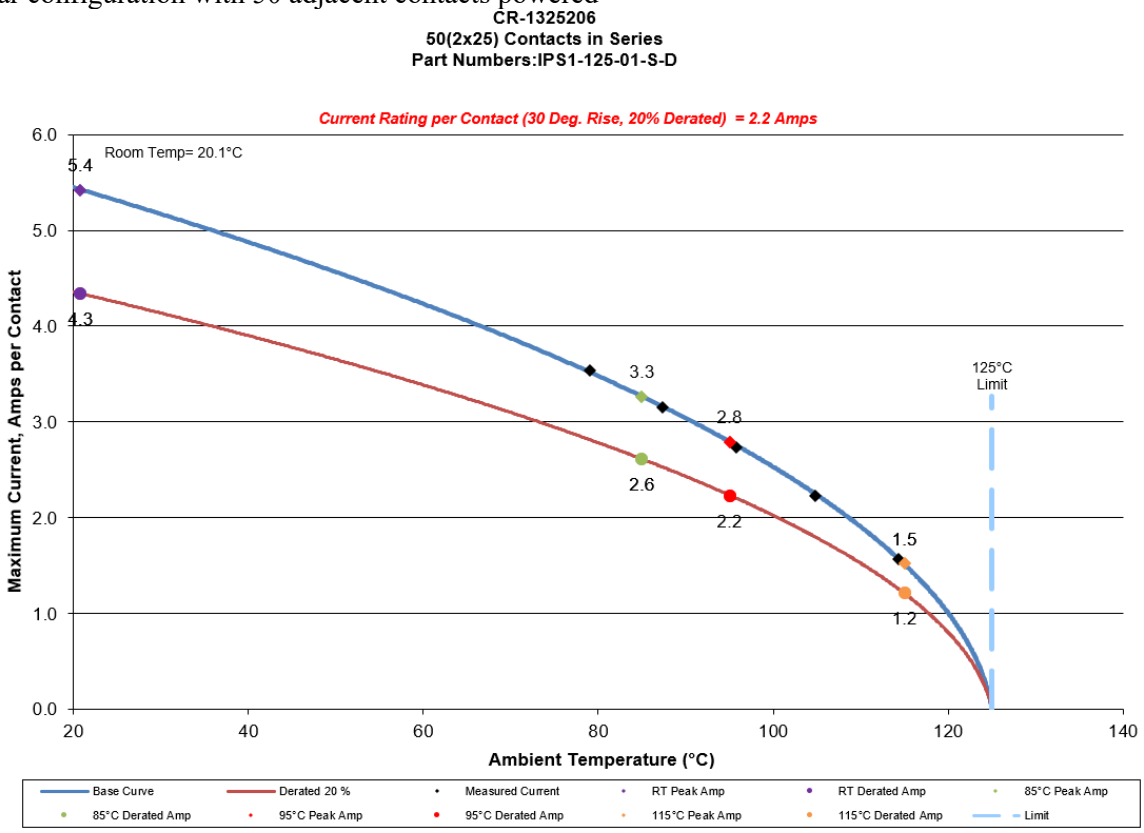
d. Linear configuration with 8 adjacent contacts powered

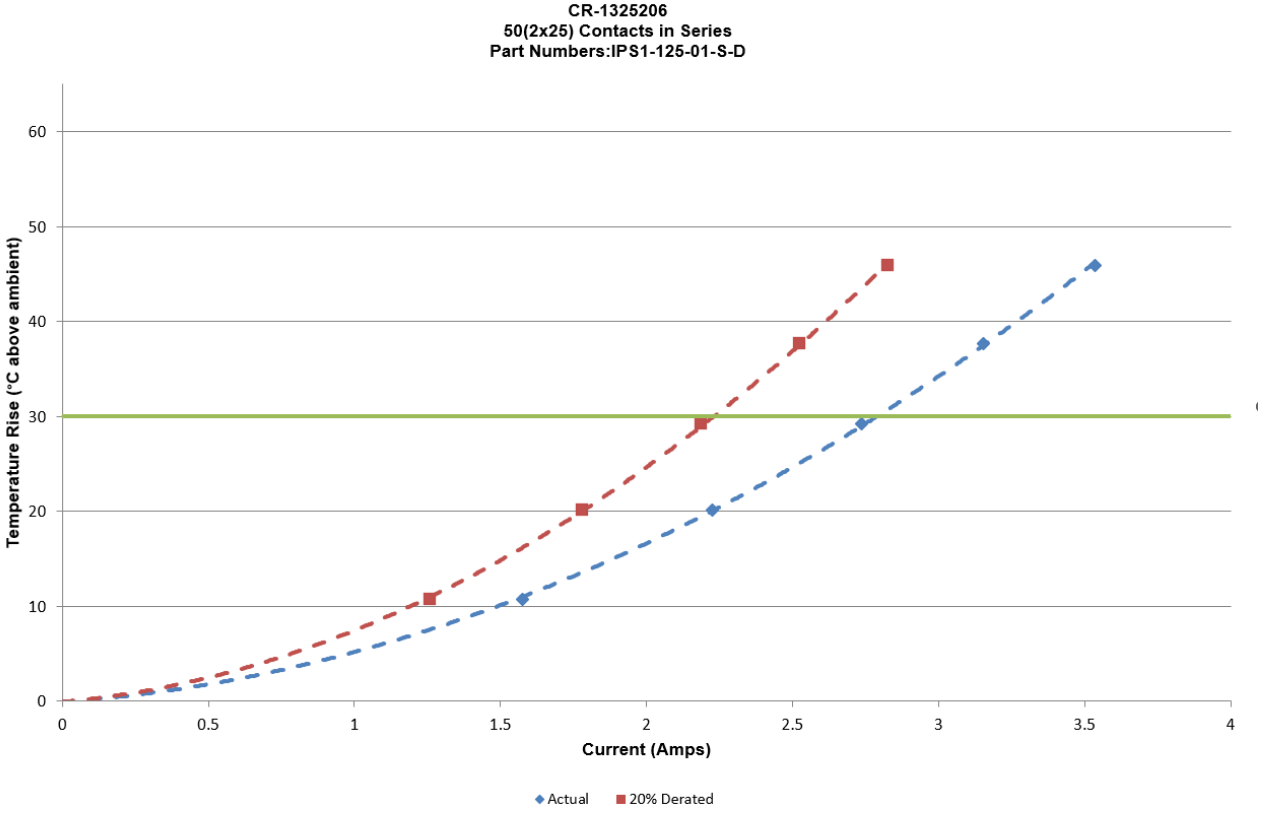




DATA SUMMARIES CONTINUED

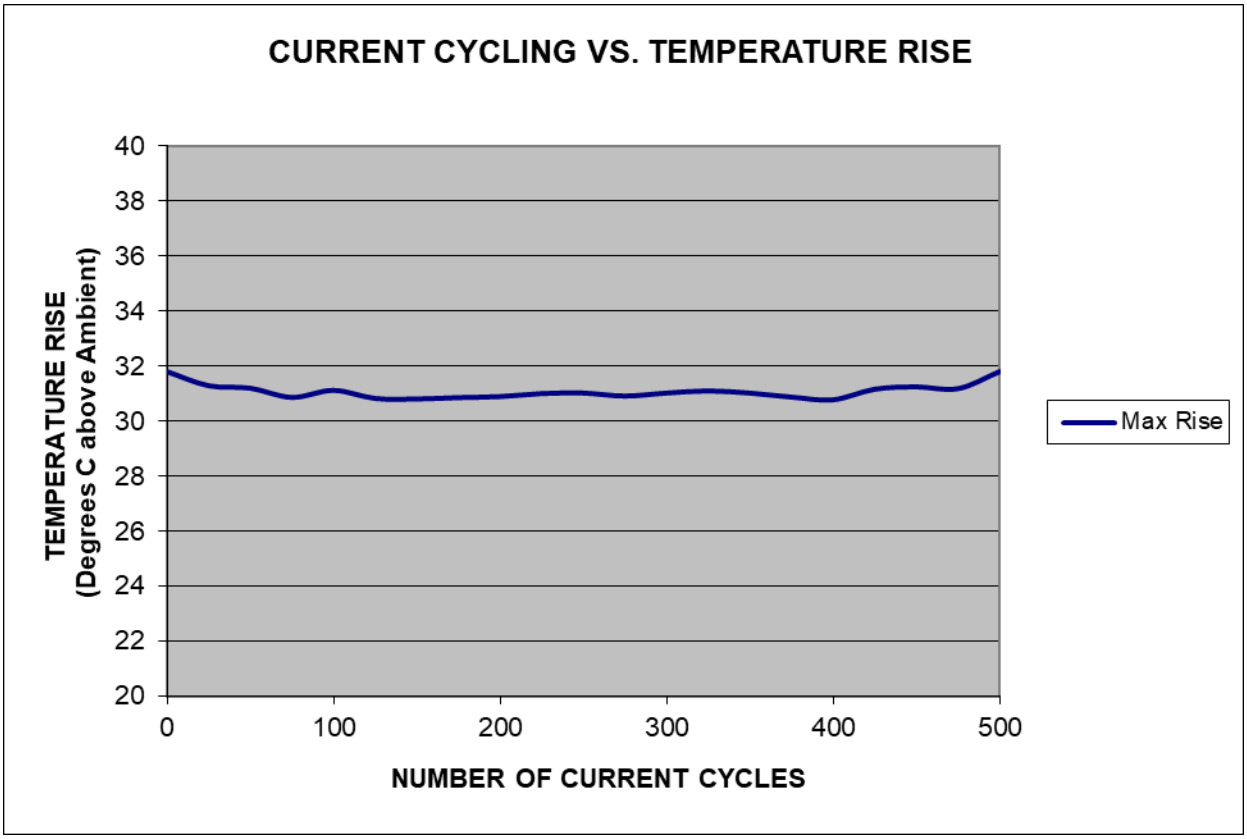
e. Linear configuration with 50 adjacent contacts powered





DATA SUMMARIES Continued

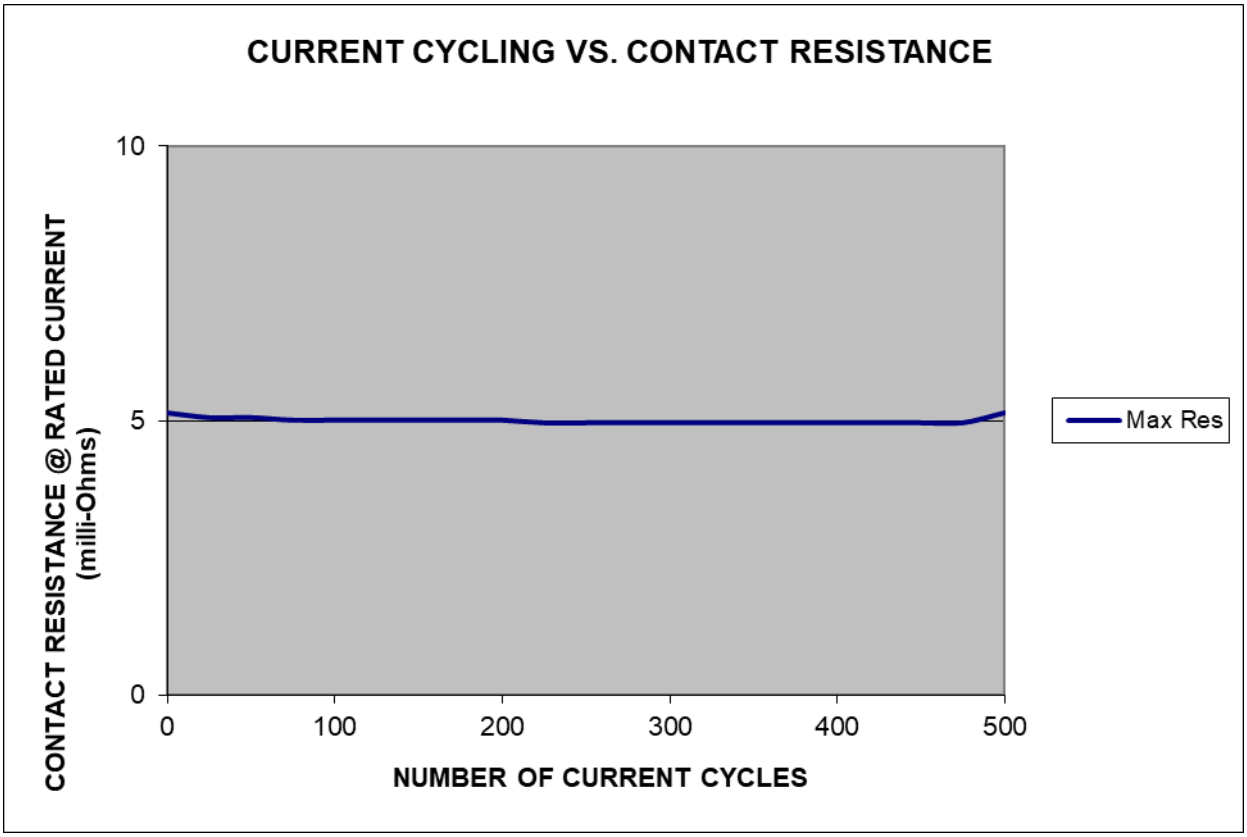
Current Cycling



TEMPERATURE RISE DATA
ALL CONTACTS ENERGIZED
(Degrees Celsius above ambient)

	INITIAL	50 CYCLES	100 CYCLES	200 CYCLES	500 CYCLES
Min	28.2	27.1	26.8	27	28.2
Max	31.8	31.2	31.1	30.9	31.8
Avg	30.4	29.5	29.4	29.3	30.4

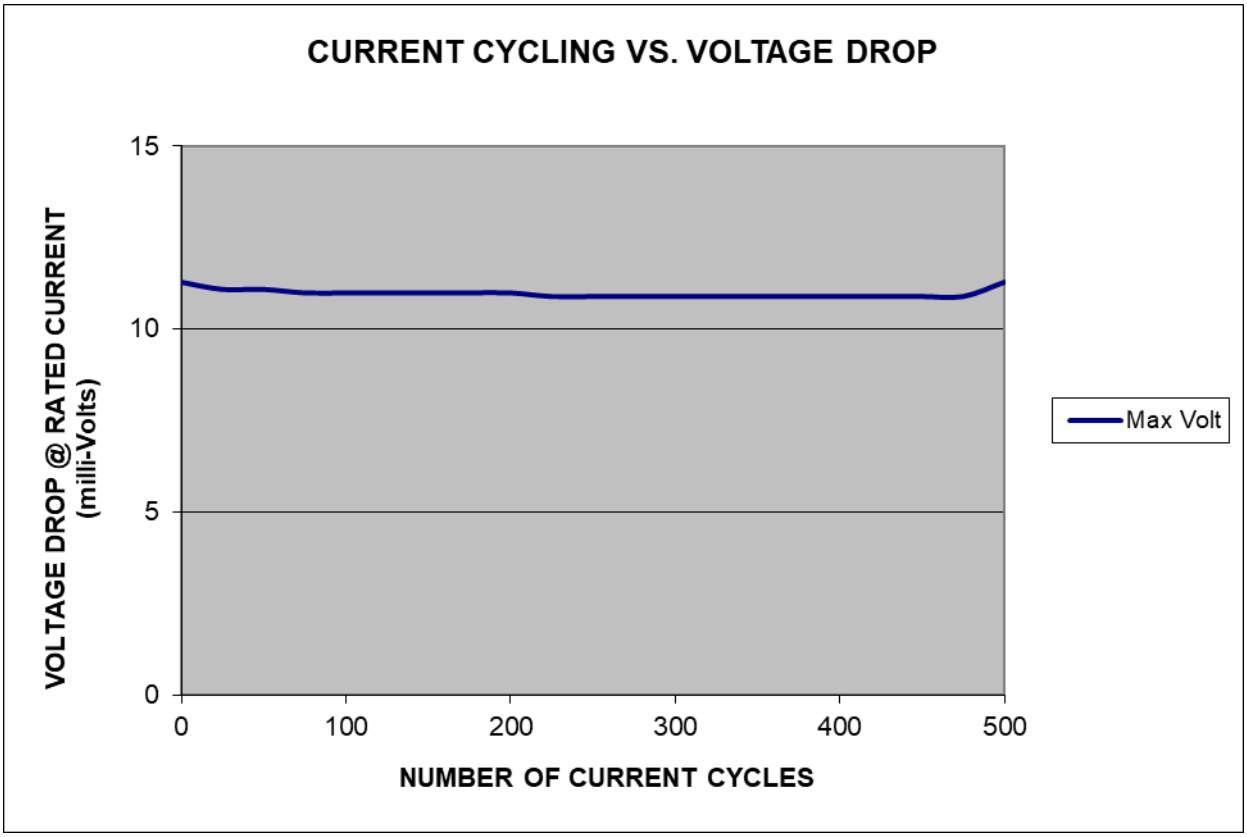
DATA SUMMARIES Continued



CONTACT RESISTANCE DATA
ALL CONTACTS ENERGIZED
(mΩ)

	INITIAL	50 CYCLES	100 CYCLES	200 CYCLES	500 CYCLES
Min	4.45	4.41	4.36	4.36	4.45
Max	5.14	5.05	5	5	5.14
Avg	4.69	4.61	4.6	4.58	4.69

DATA SUMMARIES Continued



VOLTAGE DROP DATA
ALL CONTACTS ENERGIZED
(MV)

	INITIAL	50 CYCLES	100 CYCLES	200 CYCLES	500 CYCLES
Min	9.8	9.7	9.6	9.6	9.8
Max	11.3	11.1	11	11	11.3
Avg	10.32	10.13	10.11	10.07	10.32

DATA SUMMARIES Continued

INSULATION RESISTANCE (IR):

	Pin to Pin		
	Mated	Unmated	Unmated
Minimum	**IPS1/IPT1**	**IPS1**	**IPT1**
Initial	45000	45000	45000
Thermal	6100	45000	13400
Humidity	45000	45000	45000

	Row to Row		
	Mated	Unmated	Unmated
Minimum	**IPS1/IPT1**	**IPS1**	**IPT1**
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	**IPS1/IPT1**
Break Down Voltage	2257
Test Voltage	1693
Working Voltage	564

Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued

LLCR Shock & Vibration:

1). A total of 192 signals points were measured.
2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ----------Stable
   b. +5.1 to +10.0 mOhms: ----------Minor
   c. +10.1 to +15.0 mOhms: ----------Acceptable
   d. +15.1 to +50.0 mOhms: ----------Marginal
   e. +50.1 to +1000 mOhms ----------Unstable
   f. >+1000 mOhms: ----------Open Failure

LLCR Results for Test: S&V	
Series: IPT1-125-01-S-D/IPS1-125-01-S-D	

LLCR Measurement Summaries by Pin Type		
Date	2026/4/8	2026/4/17
Room Temp (Deg C)	23	23
Rel Humidity (%)	50	50
Technician	Danton Gan	Danton Gan
mOhm values	Actual **Initial**	**Delta Shock-Vib**
	Pin Type: Signal 1	
Average	3.65	0.26
St. Dev.	0.19	0.26
Min	2.9	0
Max	4.25	1.89
Summary Count	192	192
Total Count	192	192

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Shock-Vib	**192**	**0**	**0**	**0**	**0**	**0**

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-MO-05
Description: Micro-ohmmeter
Manufacturer: Keithley
Model: 3706
Serial #: 1285188
Accuracy: Last Cal: 9/26/2025, Next Cal: 9/25/2026

Equipment #: HZ-MO-01
Description: Multimeter /Data Acquisition System
Manufacturer: Keithley
Model: 2700
Serial #: 1199807
Accuracy: See Manual
… Last Cal: 07/01/2025, Next Cal: 06/30/2026

Equipment #: HZ-THC-01
Description: Humidity transmitter
Manufacturer: Thermtron
Model: SM-8-8200
Serial #: 38846
Accuracy: Last Cal: 2/28/2025, Next Cal: 2/27/2026

Equipment #: HZ-TSC-01
Description: Vertical Thermal Shock Chamber
Manufacturer: Cincinnatti Sub Zero
Model: VTS-3-6-6-SC/AC
Serial #: 10-VT14994
Accuracy: See Manual
… Last Cal: 06/28/2025, Next Cal: 06/27/2026

Equipment #: SVC-01
Description: Shock & Vibration Table
Manufacturer: Data Physics
Model: LE-DSA-10-20K
Serial #: 10037
Accuracy: See Manual
… Last Cal: 04/22/2025, Next Cal: 04/22/2026

Equipment #: ED-03
Description: Event Detector
Manufacturer: Analysis Tech
Model: 32EHD
Serial #: 1100604
Accuracy: See Manual
… Last Cal: 10/31/2024, Next Cal: 10/31/2025